



Universität Augsburg
Mathematisch-Naturwissenschaftlich-
Technische Fakultät

Seminar on Physics of Thin Films

SP-STM & MExFM

Jonas Kell – jonas.kell@student.uni-augsburg.de

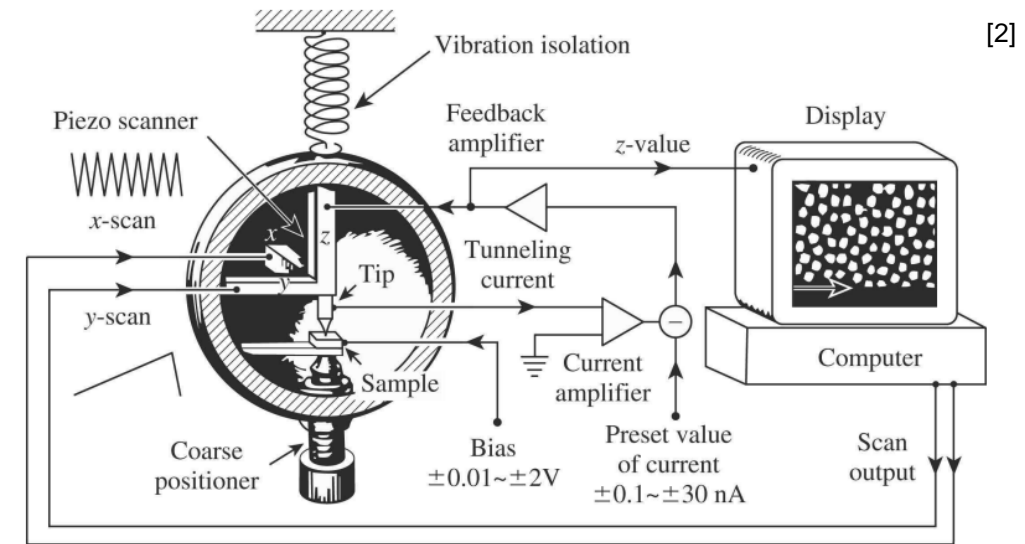
Augsburg, 08.12.2022

Outline: Spin-Polarized-Scanning-Tunneling-Microscope

- 1 General Functionality & Construction
- 2 Spin Resolved/Polarized STM (SP-STM)
- 3 Experiments & Applications
- 4 Outlook: Magnetic Exchange Force Microscopy (MExFM)
- 5 Summary and Conclusion

Construction & Current Feedback Mechanism

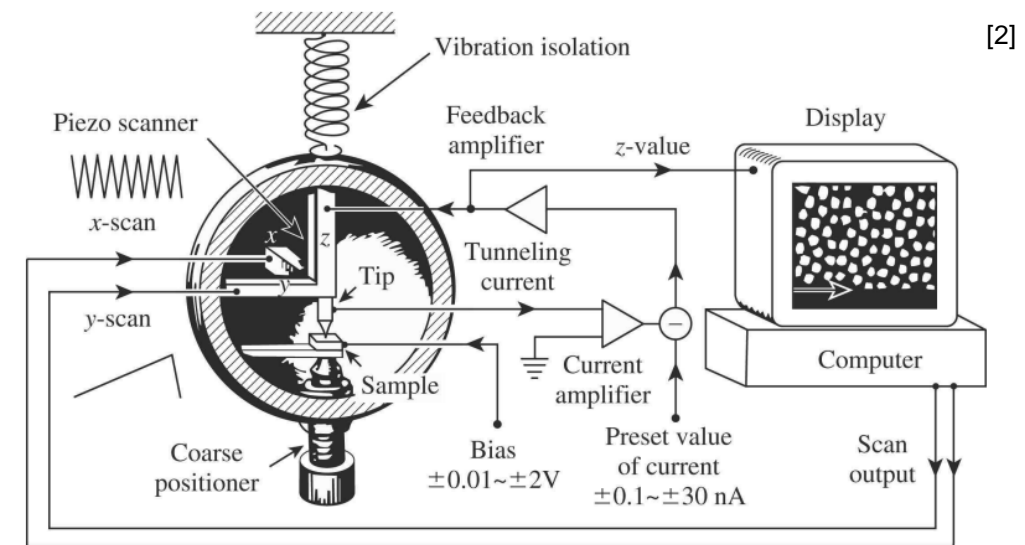
General Functionality & Construction



Construction & Current Feedback Mechanism

General Functionality & Construction

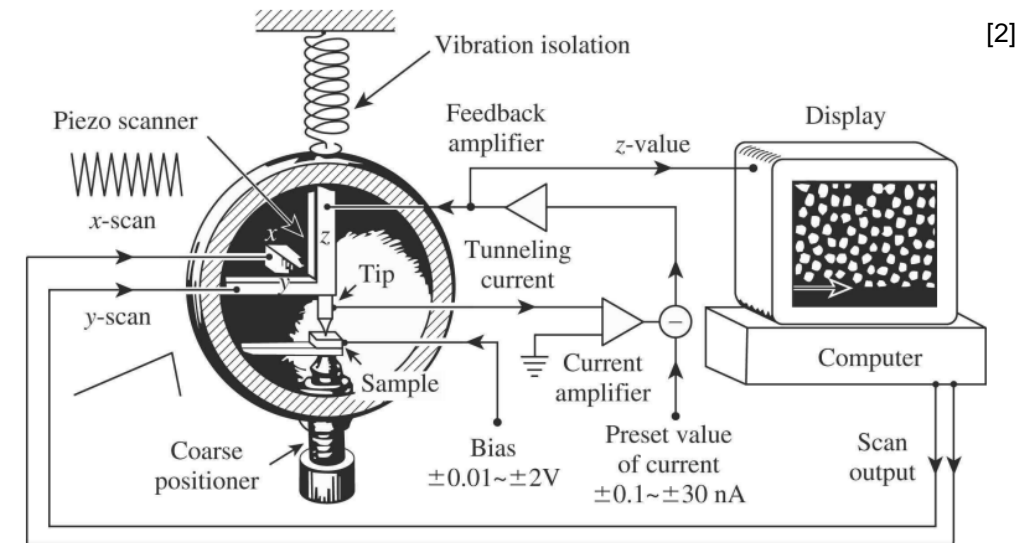
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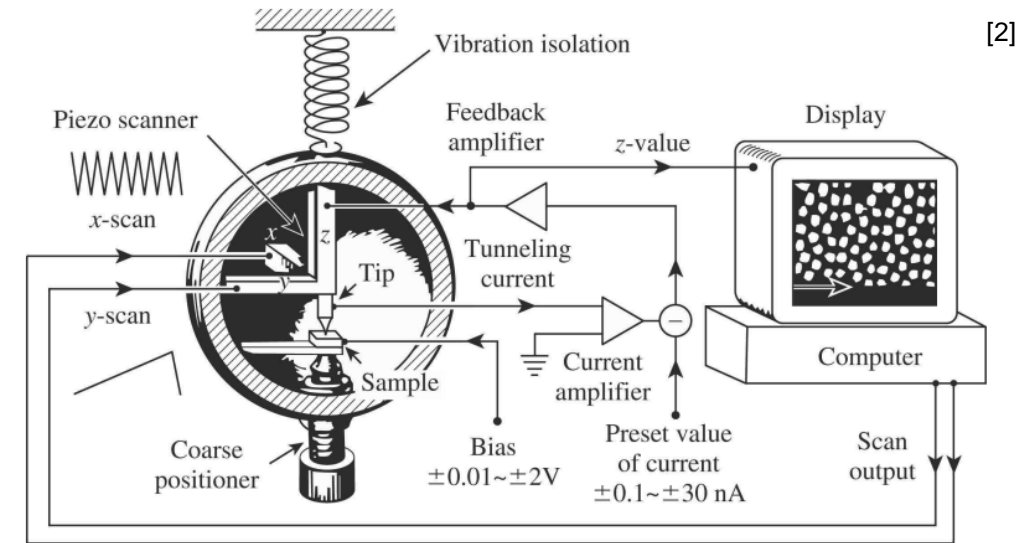
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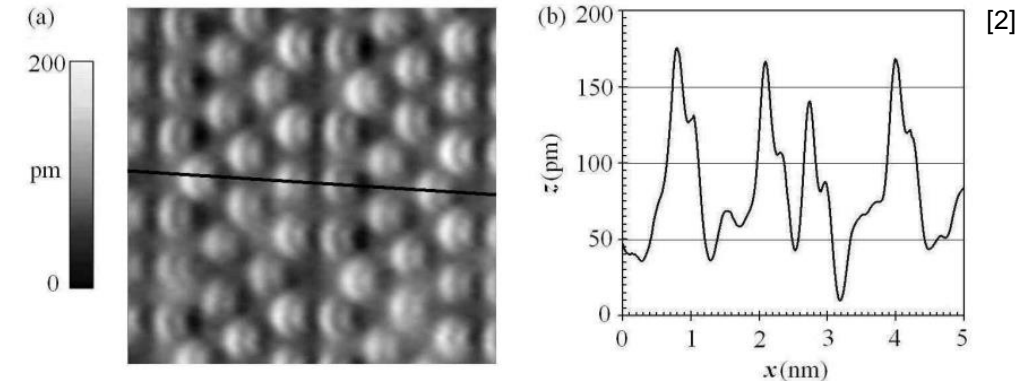
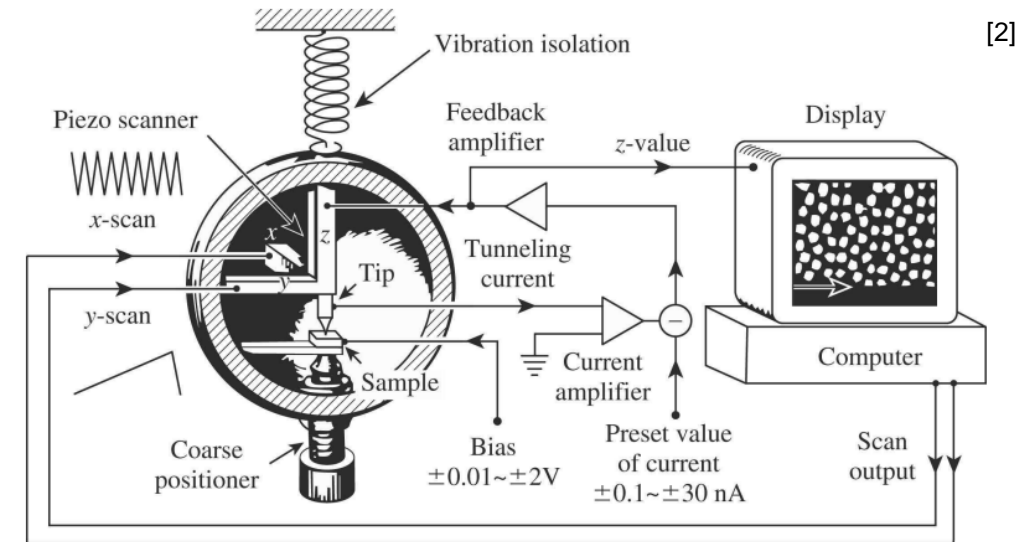
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- Combination with different control signals produces different scanning modes
 - A-Scan (dot, often time resolved)
 - B-Scan (line)
 - C-Scan (surface)

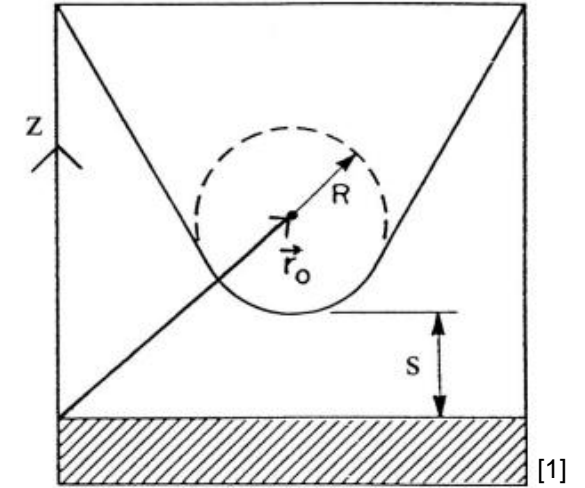


Mathematics of the Tunneling Process

General Functionality & Construction

- The tunneling current depends:
 - On the “local density of states” (LDOS, here n_s)
 - The bias voltage U
 - The distance to the sample S
 - The exponential dependency is key to the high resolution capability

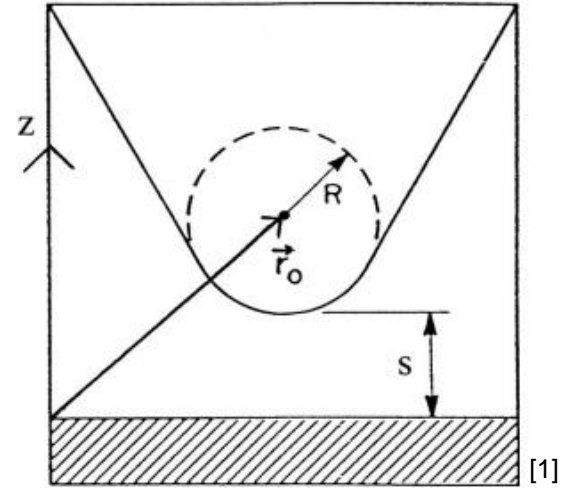
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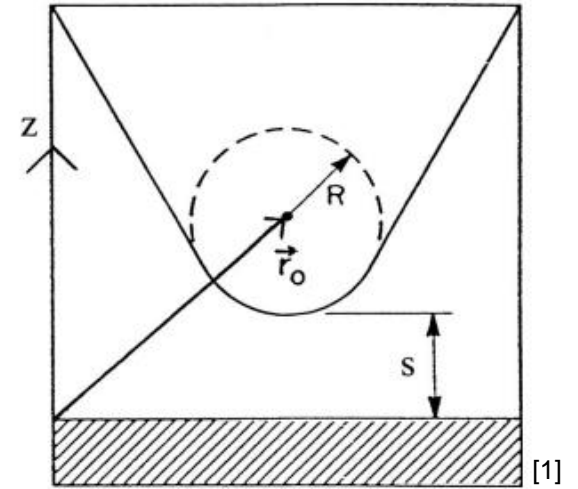
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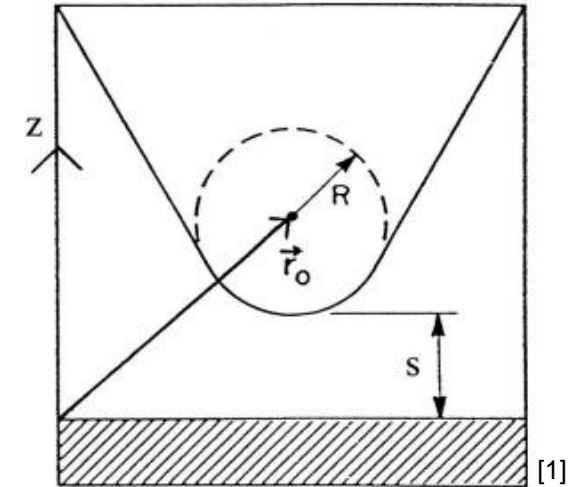
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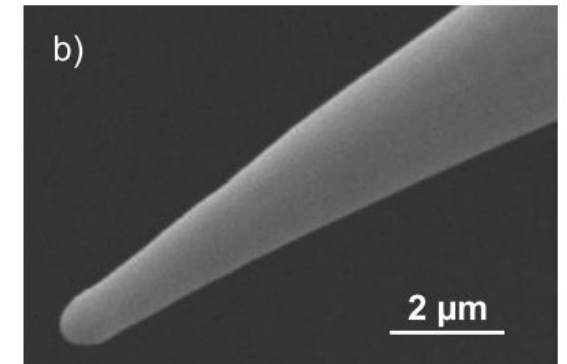
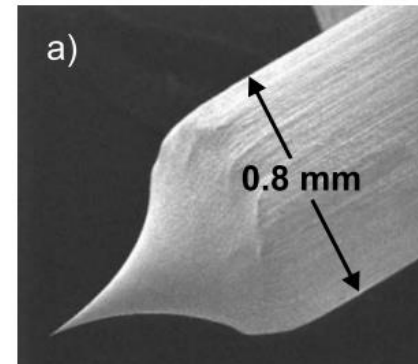
$$\Psi_\mu = \frac{1}{R} e^{-\kappa R}$$

$$I \propto \exp(-2\kappa S)$$

Environment & Generating Tips

General Functionality & Construction

- Temperature range generally in the region of mK to some K
- Measuring at atom-scale resolution generally requires ultra-high-vacuum (UHV) setups

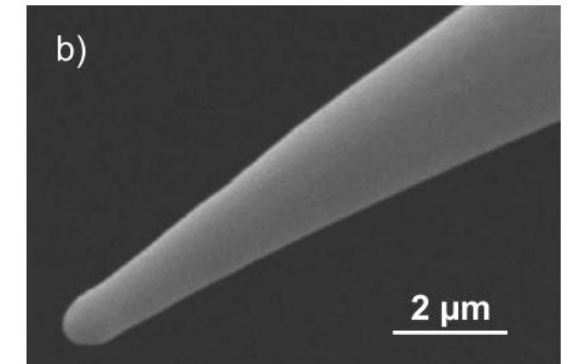
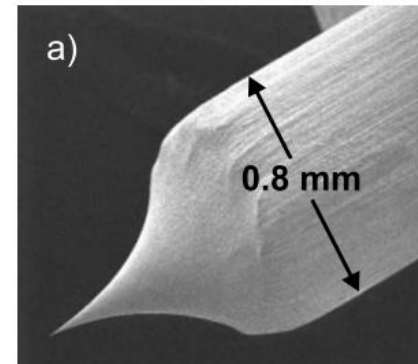


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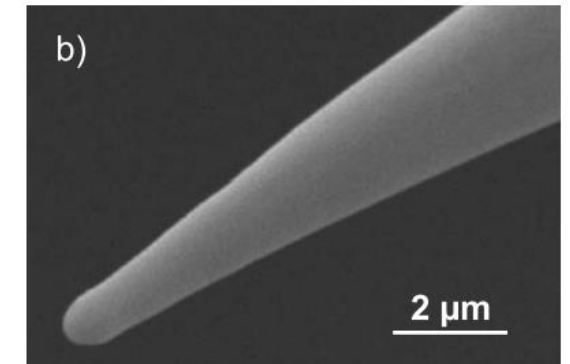
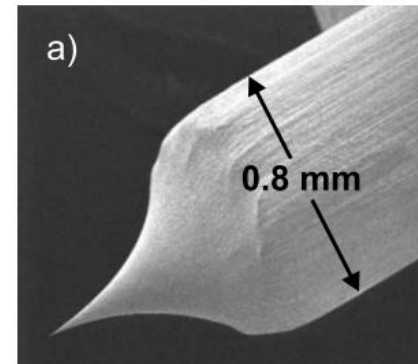


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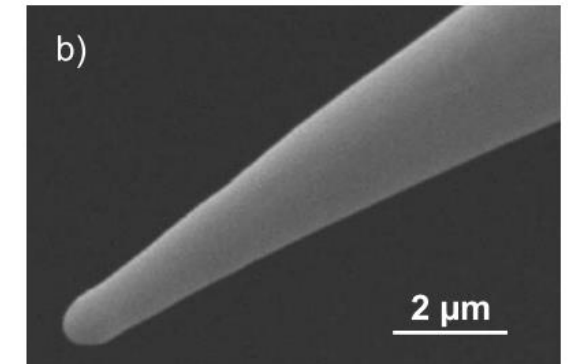
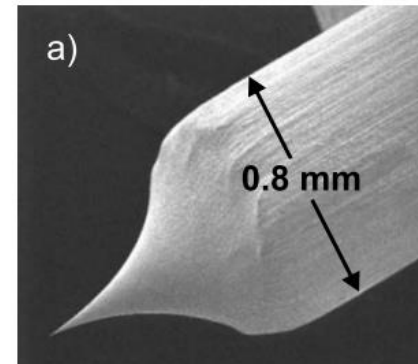


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- Tip preparation
 - Generally performed *in situ* to avoid contaminations
 - Pulling procedures
 - Electrochemical etching methods
 - Cleanup through electron/ion bombardment

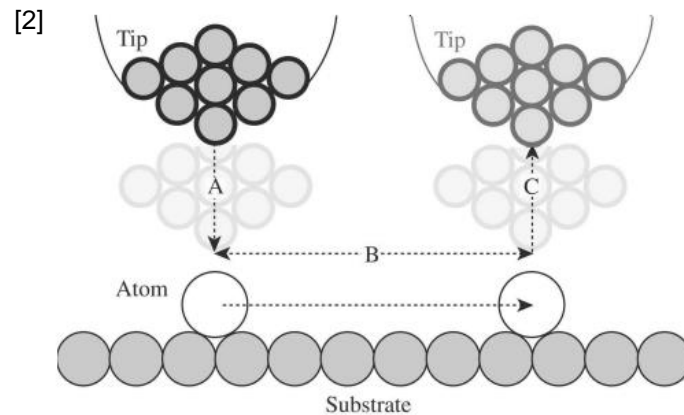


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Example: Manipulation of individual atoms

General Functionality & Construction

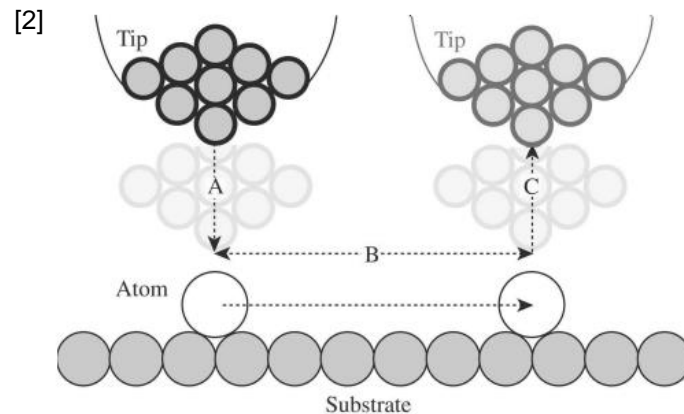
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- Multiple applications
 - Data storage
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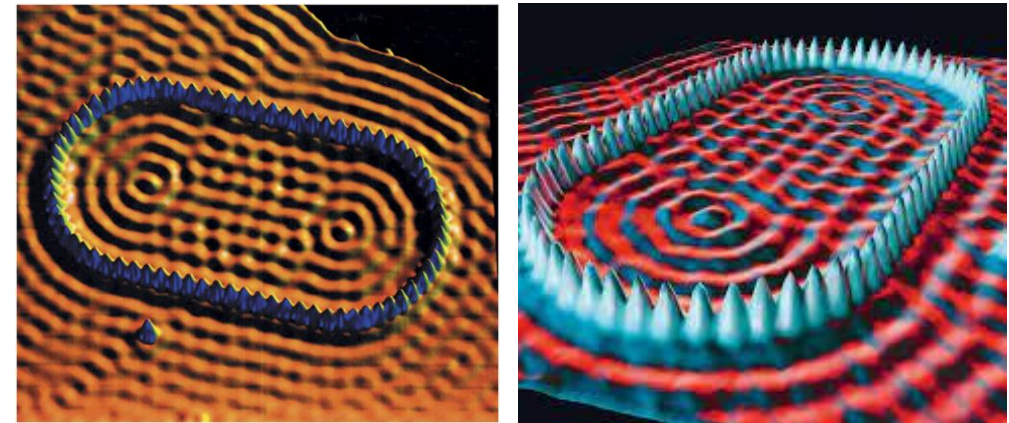


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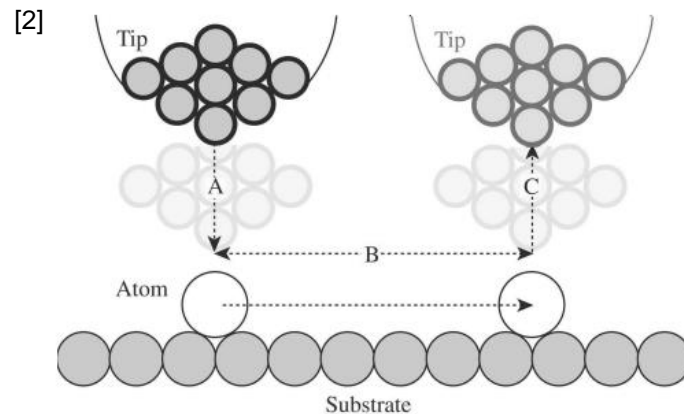
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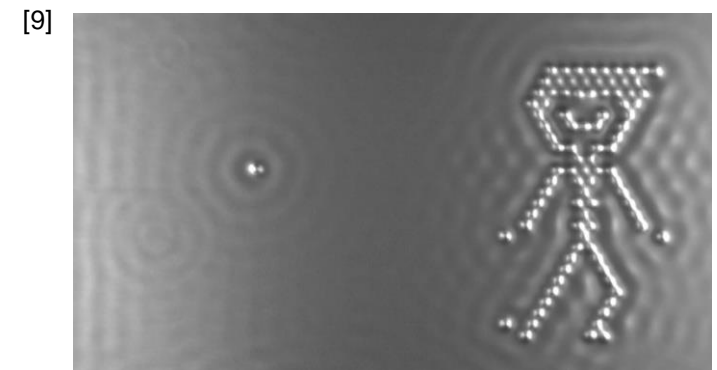
■ “Quantum Corrals”



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[2]

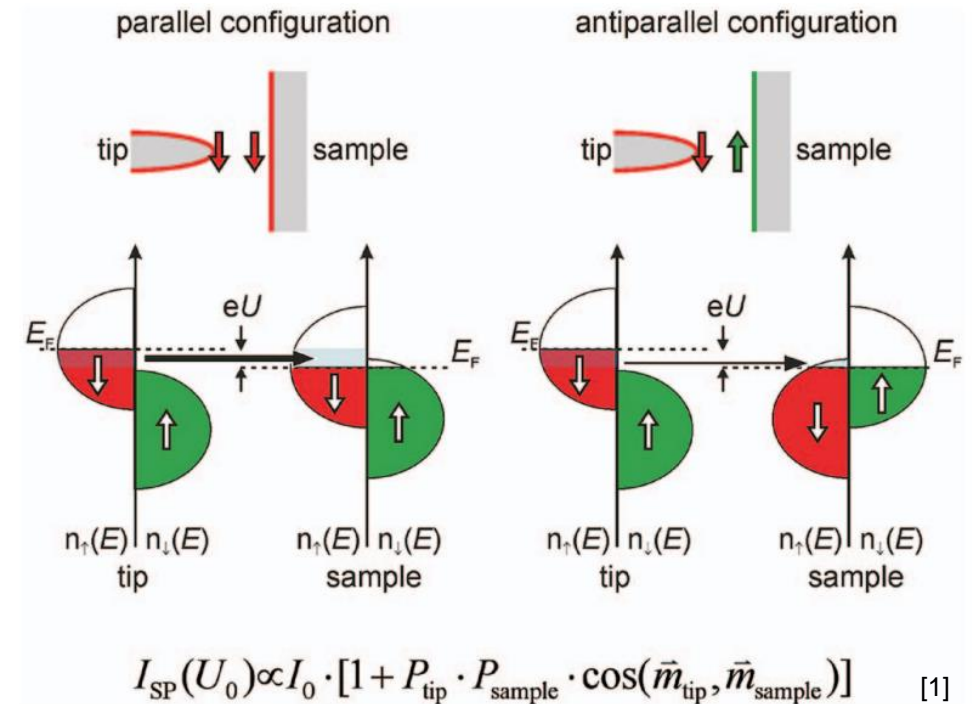


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Theory of the Spin Resolved STM

Spin Resolved/Polarized STM (SP-STM)

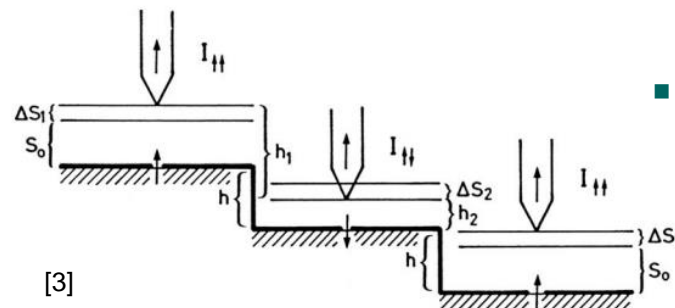
- The model for a spin-dependent ferromagnet-ferromagnet tunnel junction is applied
- The local densities of states for tip and sample
 - $n_t = n_t^{\uparrow} + n_t^{\downarrow}, \quad n_s = n_s^{\uparrow} + n_s^{\downarrow}$
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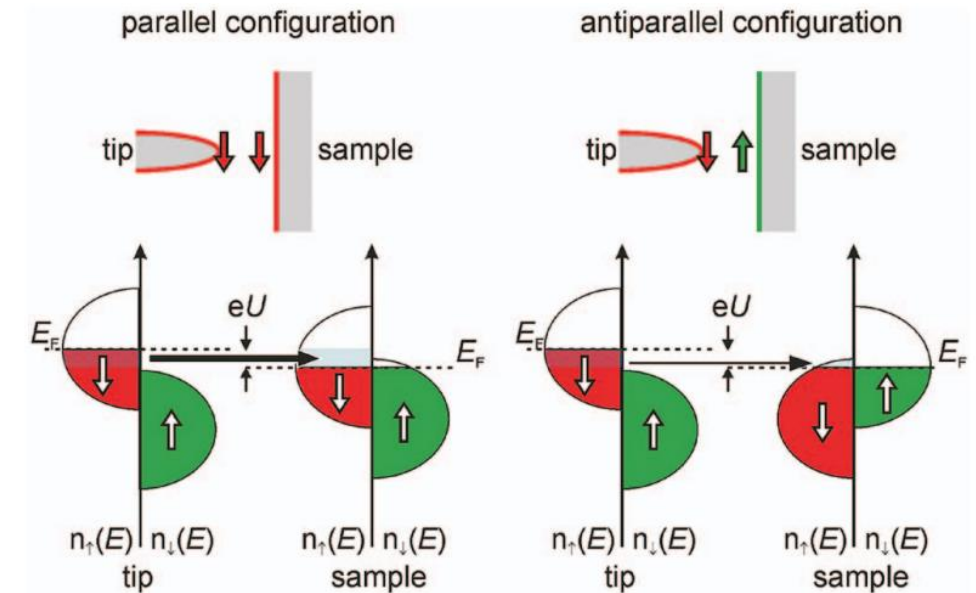
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 - $P_t = m_t/n_t$, $P_s = m_s/n_s$
- First time experimentally confirmed for stepped antiferromagnetic coordinated, stepped chromium surface



Sample composition

- Cr(001)
- Steps non-magnetic: 0.144nm
- Steps magnetic: 0.12nm/0.16nm



$$I_{SP}(U_0) \propto I_0 \cdot [1 + P_{tip} \cdot P_{sample} \cdot \cos(\vec{m}_{tip}, \vec{m}_{sample})] \quad [1]$$

Tip ↔ Sample Material Combinations

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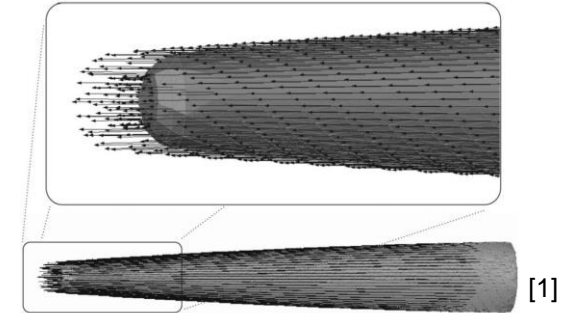
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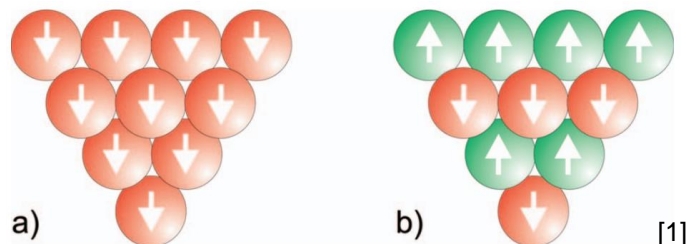
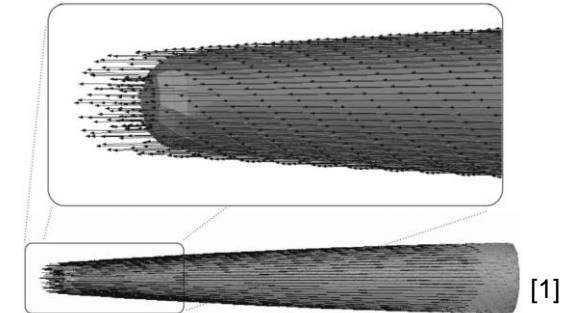
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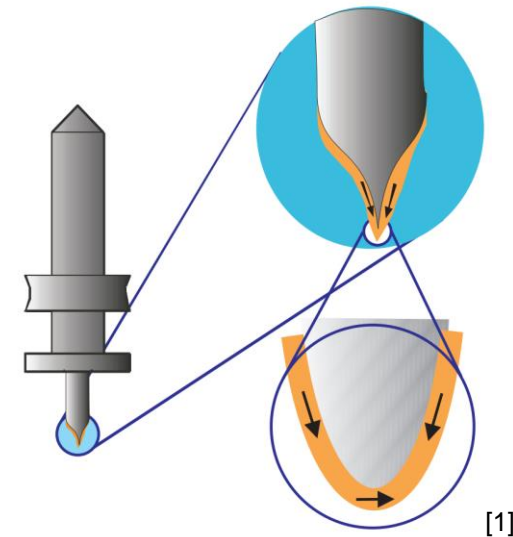
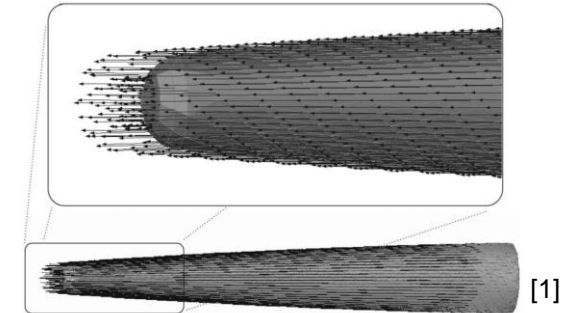
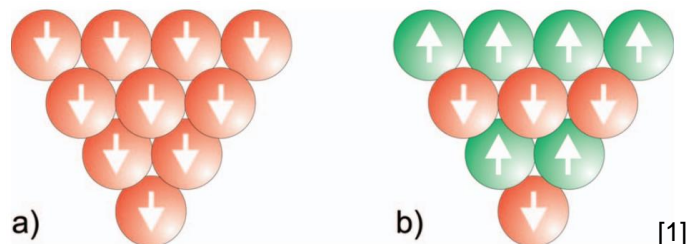
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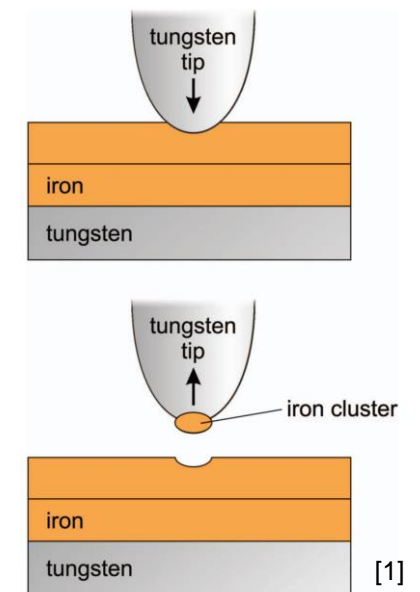
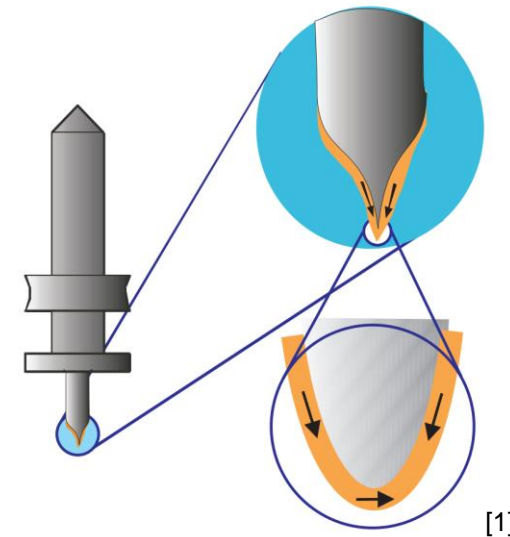
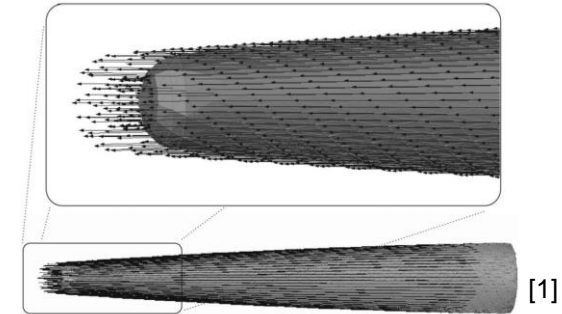
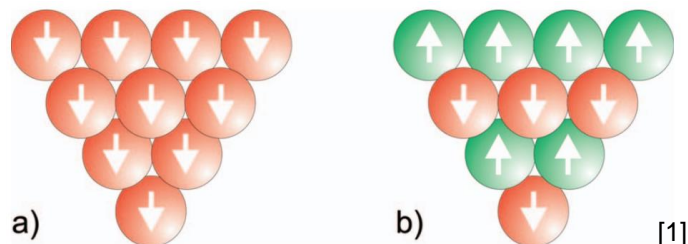
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 - Magnetic clusters bonded to the tip
 - Very easy tip generation process



Modes of Operation

Spin Resolved/Polarized STM (SP-STM)

- Constant-current
- SR-spectroscopic
- Modulated tip

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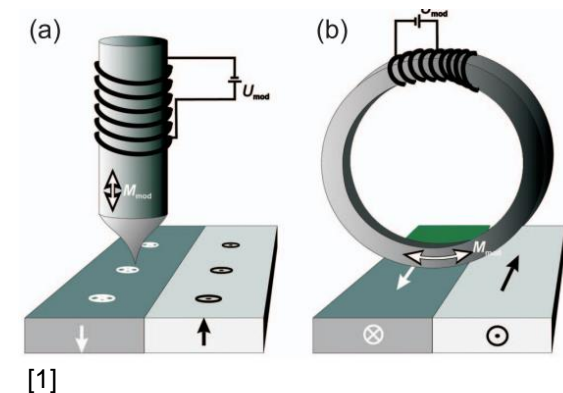
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 - Extracts energy dependency of the local electron density of states (LDOS)
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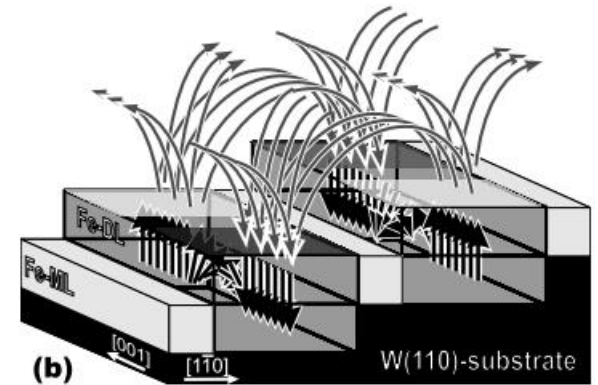
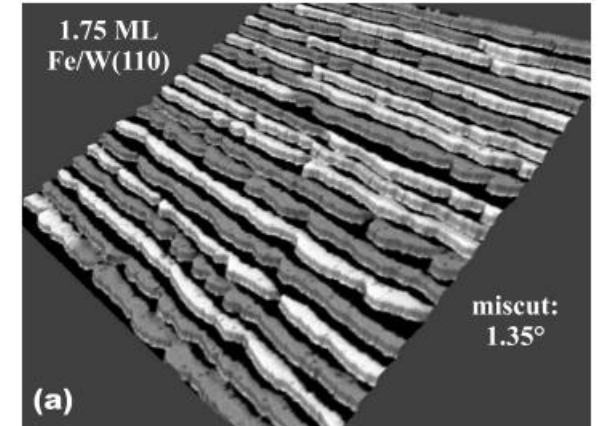
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 - Aims to provide separation between electronic structure and magnetic structure
 - Magnetization of the tip is modulated periodically
 - Additionally requires bias voltage modulation and tip distance modulation



Nanostripes on stepped Surfaces

Experiments & Applications

- Nanostripes get formed when material is deposited on stepped substrate



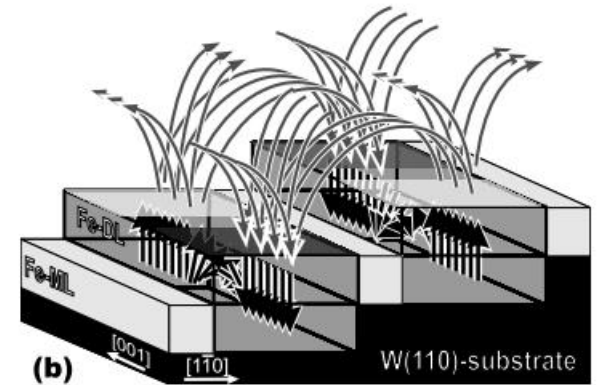
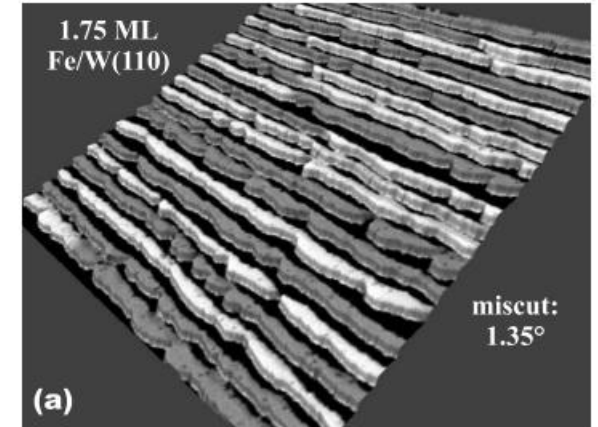
[1]

- Sample composition
 - W(110)
 - Fe monolayer
 - Fe doublelayer
 - Left, stripe-width > 10nm, right < 10nm

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- Magnetic effects may emerge that depend on the topology
 - Influence of the width?
 - Influence of the height?
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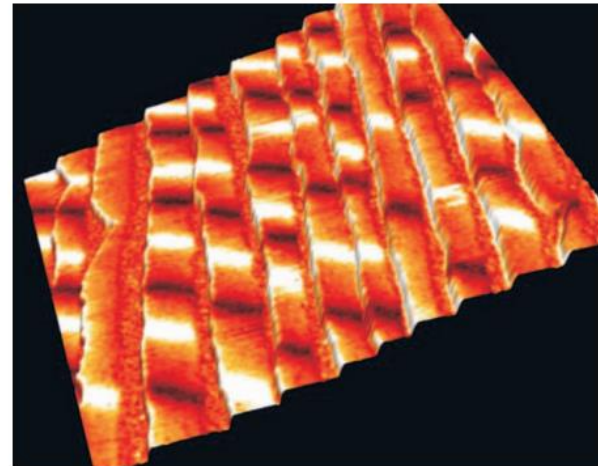
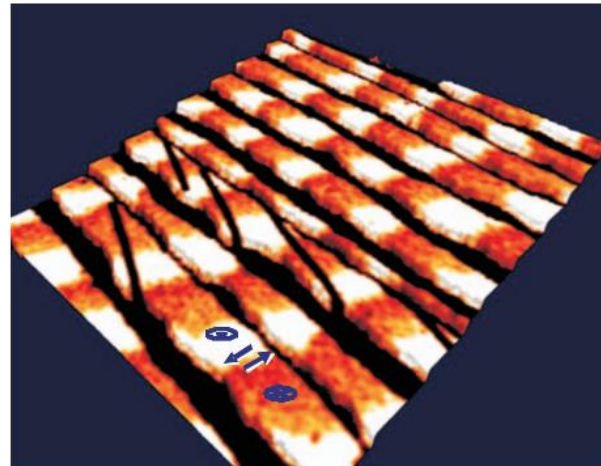
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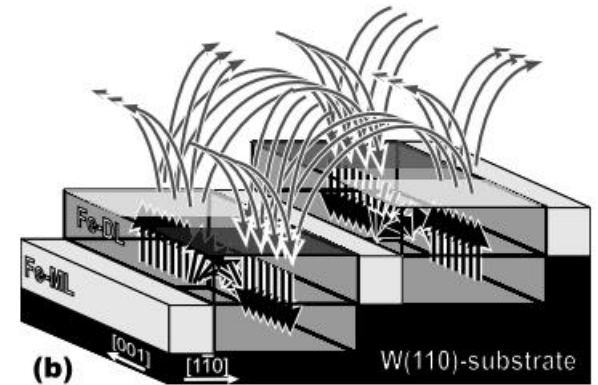
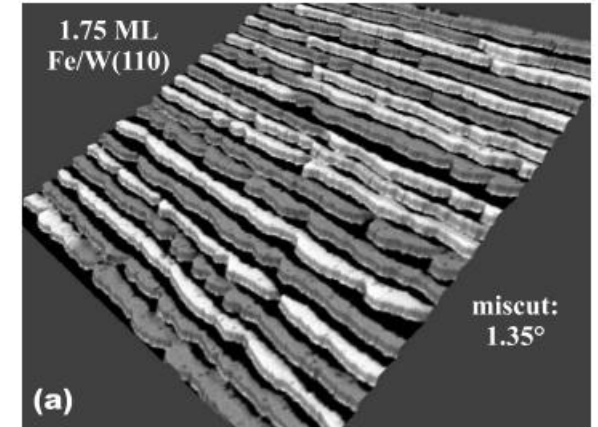
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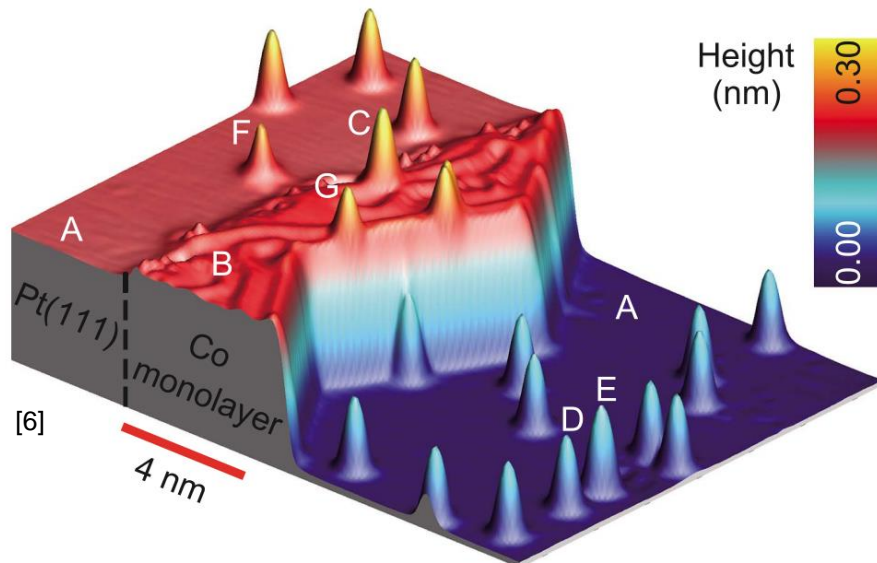
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 - Spin polarization of tip can be determined
 - Makes arguing about the spin relation surface \leftrightarrow adatom possible



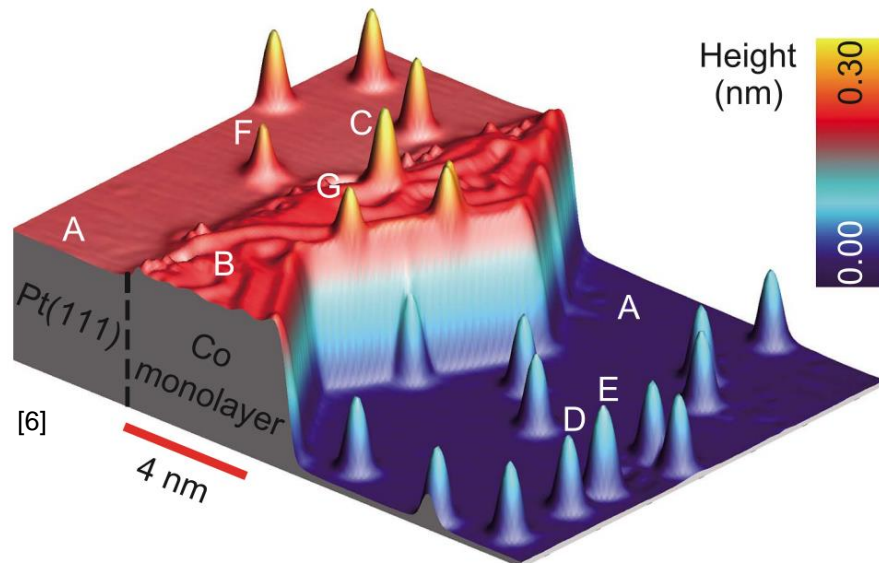
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- Co adatoms C & D
- Co dimer E

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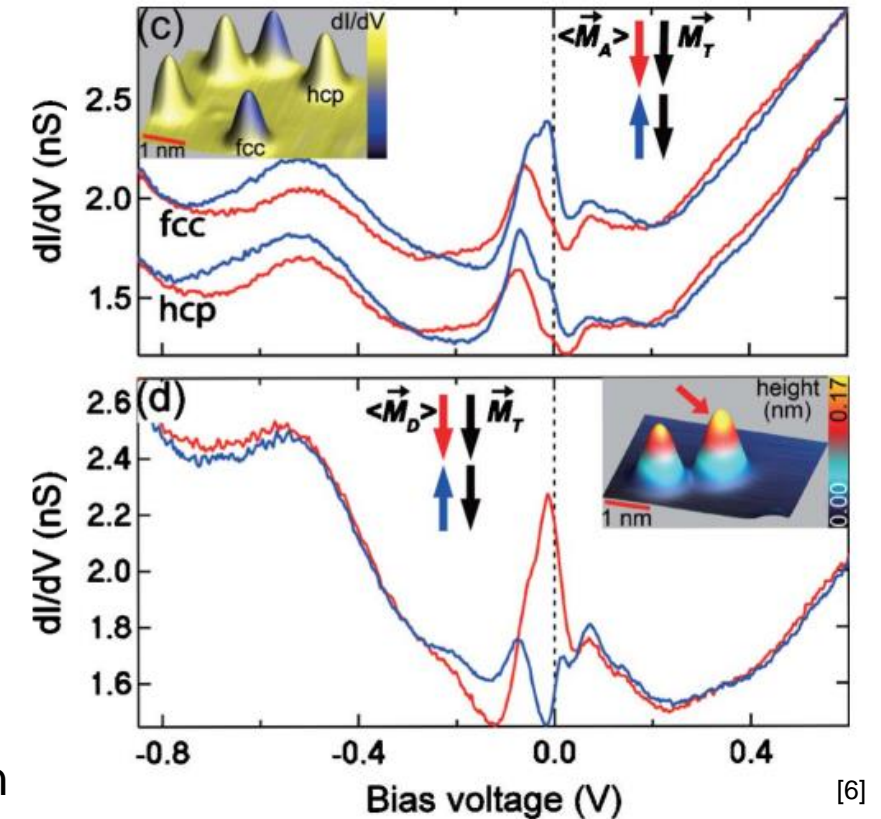
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- Spin polarization effect of large magnitude when looking at a Co-dimer



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Antiferromagnetic Arrangements

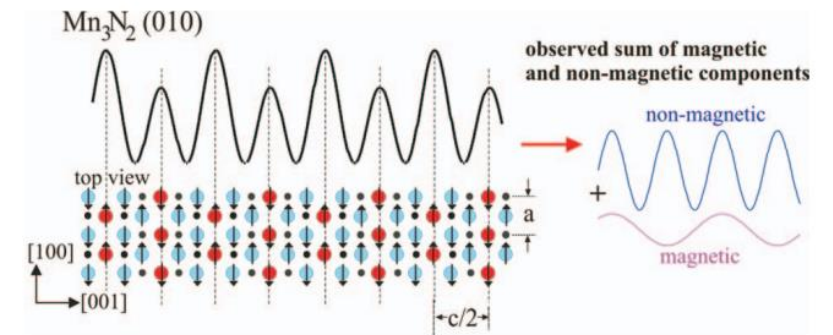
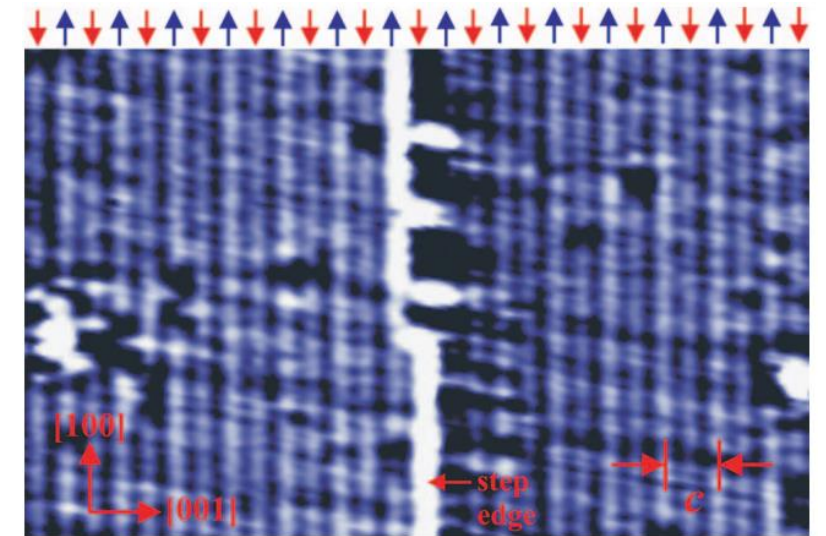
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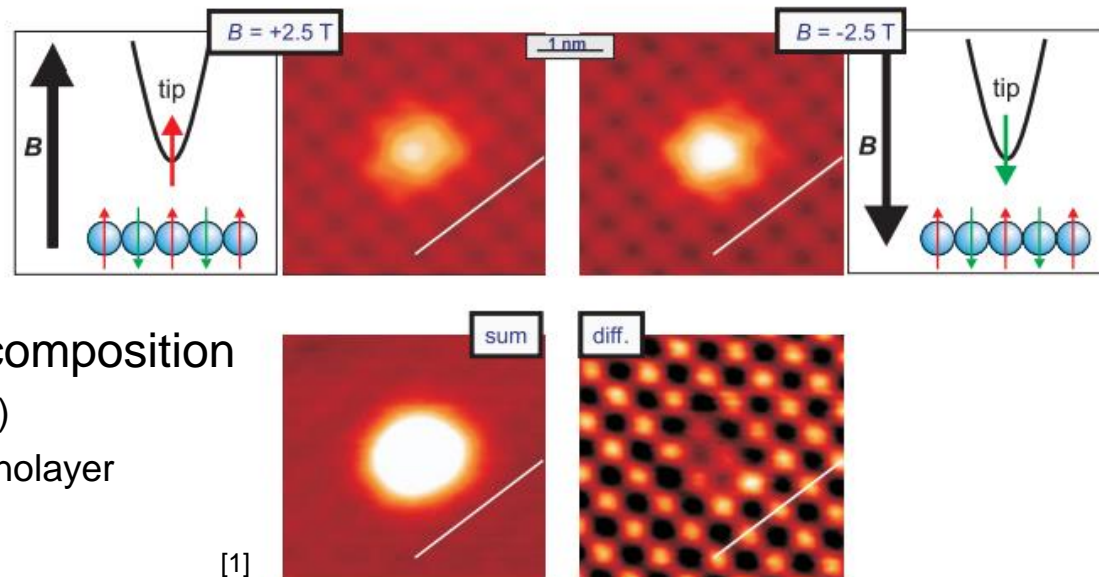
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 - $\text{Mn}_3\text{N}_2(010)$

Antiferromagnetic Arrangements

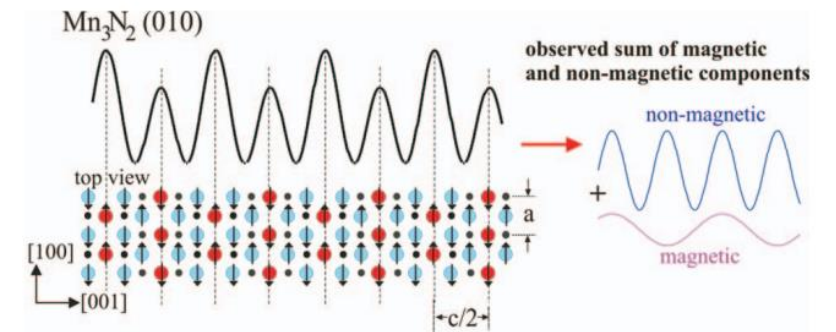
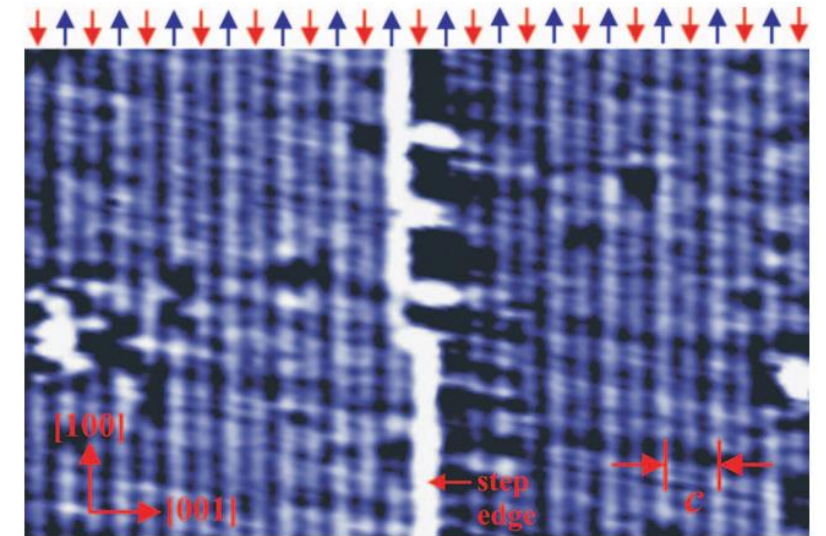
Experiments & Applications

- Averaging measuring procedures do not allow resolving antiferromagnetic superstructures
 - If magnetic unit cell is smaller than resolution, the magnetic moment is averaged and vanishes
- Topology can be affected by magnetic and non-magnetic contributions



- Sample composition

- W(001)
- Fe Monolayer



- Sample composition

- Mn₃N₂(010)

Time Resolved Experiments

Experiments & Applications

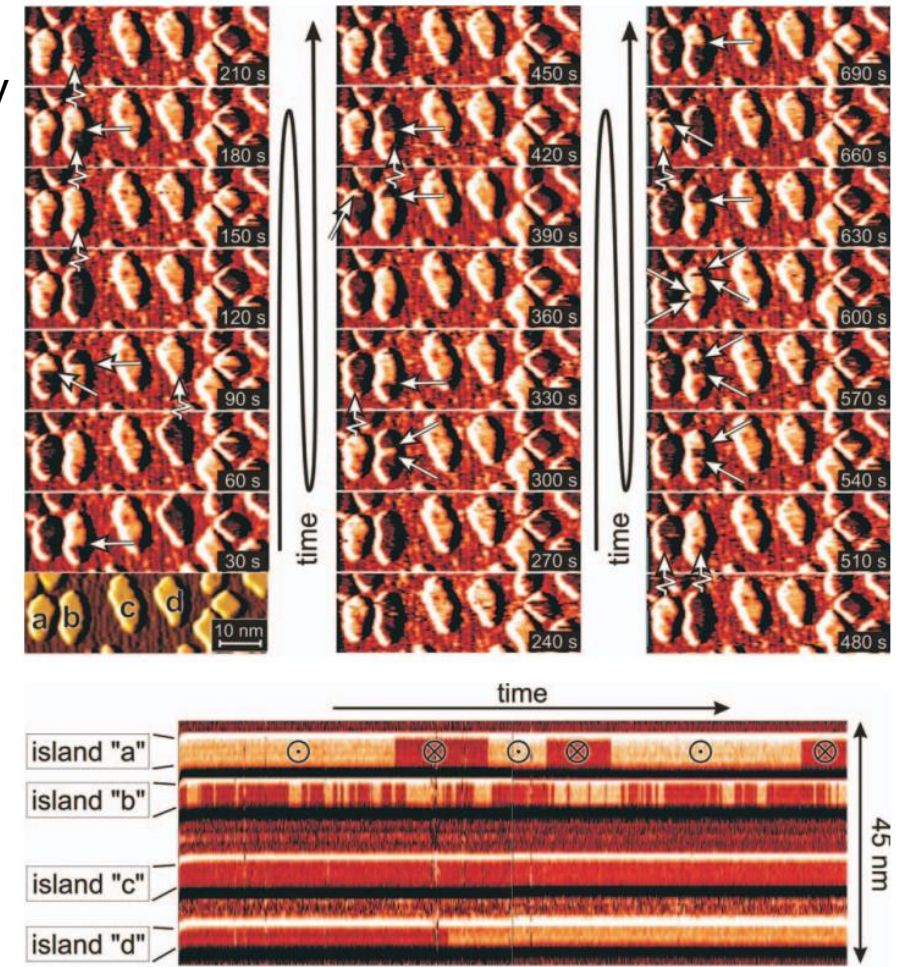
- SP-STM does not only image in real-space, but consequently also in the real-time domain

Time Resolved Experiments

Experiments & Applications

- SP-STM does not only image in real-space, but consequently also in the real-time domain

- Sample composition
 - Mo(110)
 - Fe islands (area < 40nm²)
- Antiferromagnetic tip required
 - Magnetic stray field of a ferromagnetic tip would influence switching behavior

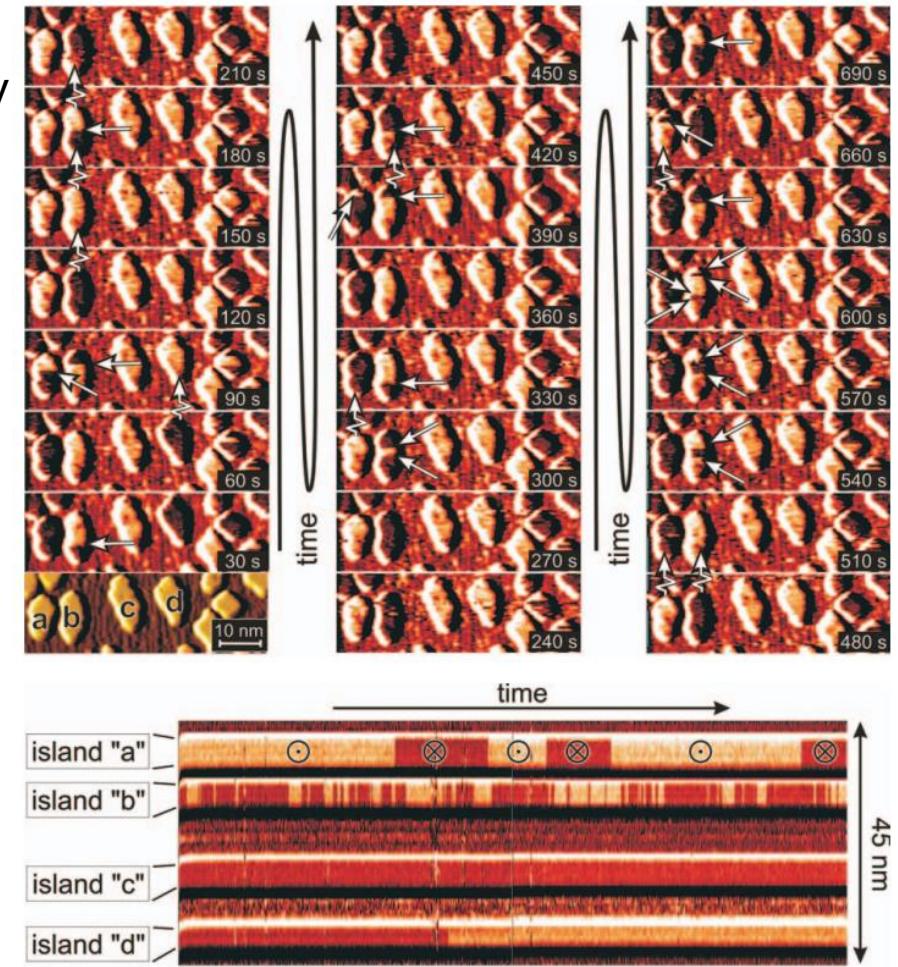


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Time Resolved Experiments

Experiments & Applications

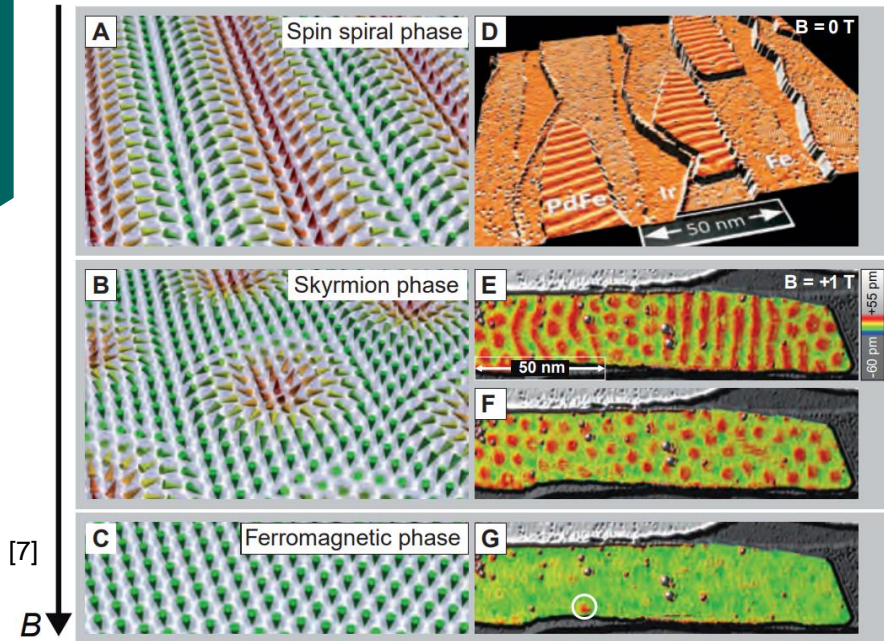
- SP-STM does not only image in real-space, but consequently also in the real-time domain
- Time resolution depends on imaging mode and spacial resolution
- Switching events most of the time thermally induced
 - May also be a result of the probe's influence or an external magnetic field
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[1]

Magnetic RAM through Skyrmion Manipulation

Experiments & Applications

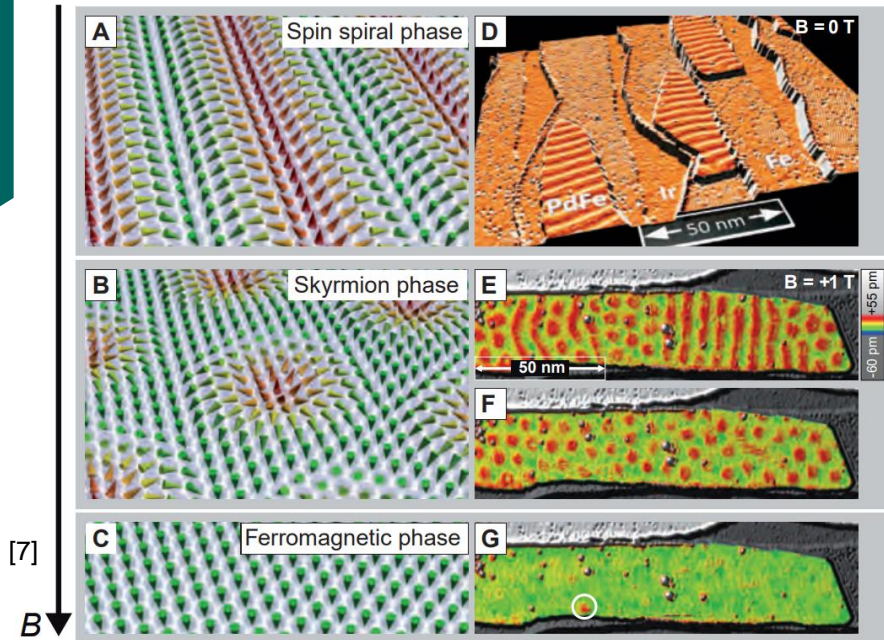


$T \sim 8 \text{ K}$

- Sample composition
 - Ir(111)
 - PdFe Bilayer

Magnetic RAM through Skyrmion Manipulation

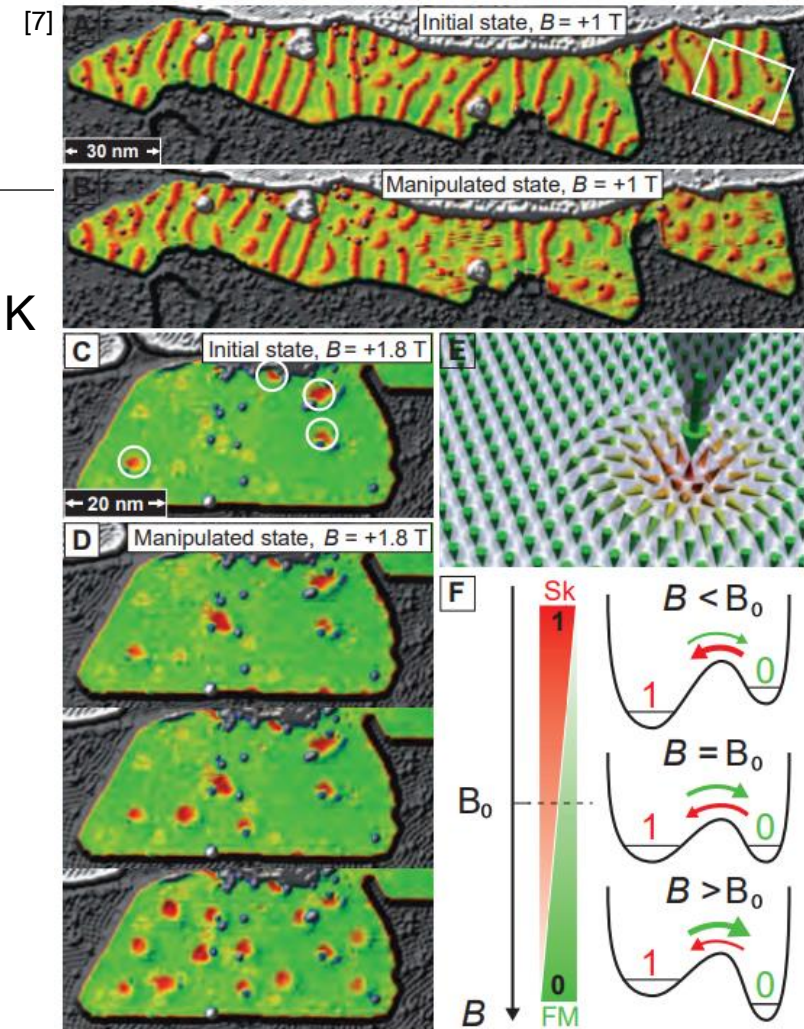
Experiments & Applications



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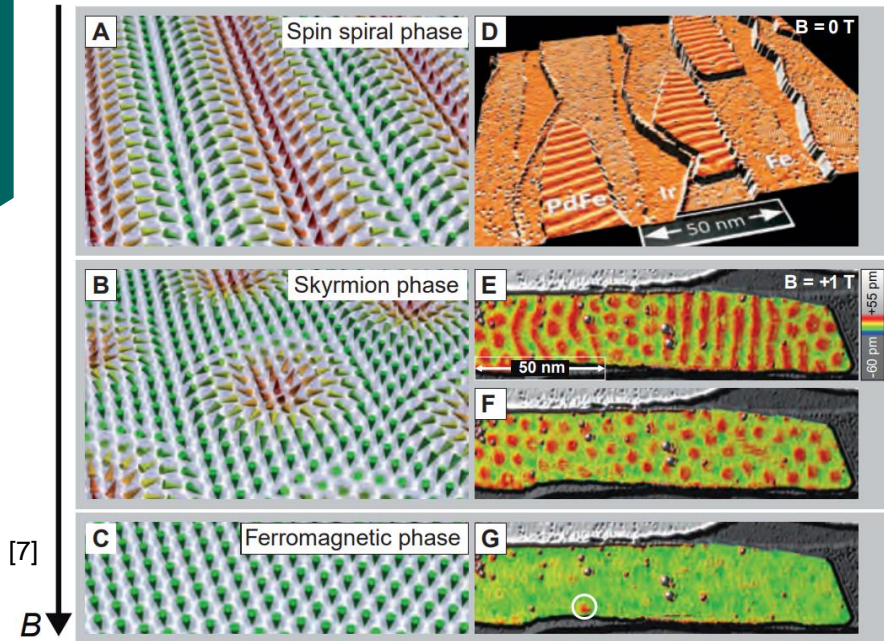
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$T \sim 4.2$ K



Magnetic RAM through Skyrmion Manipulation

Experiments & Applications

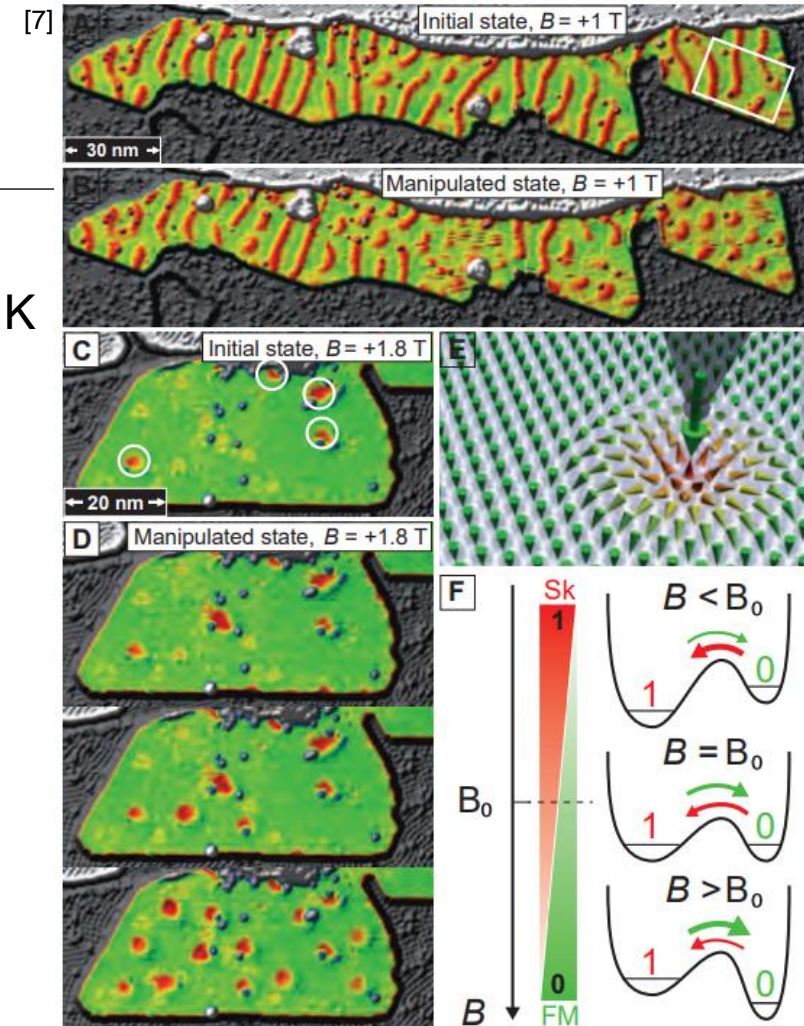


- High temperature ($T \sim 8$ K)
 - Thermal reordering possible
- Low temperature ($T \sim 4.2$ K)
 - Only induced reordering possible

$T \sim 8$ K

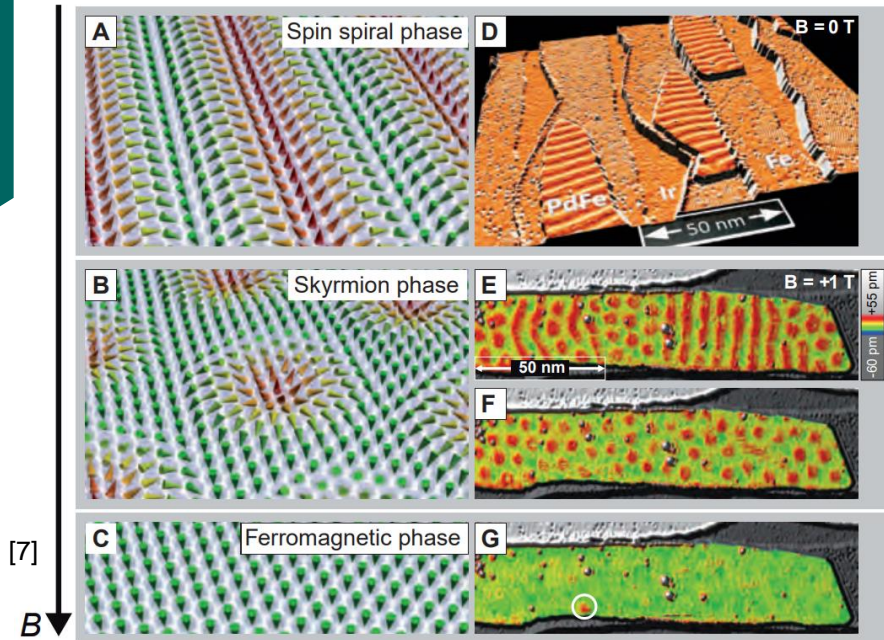
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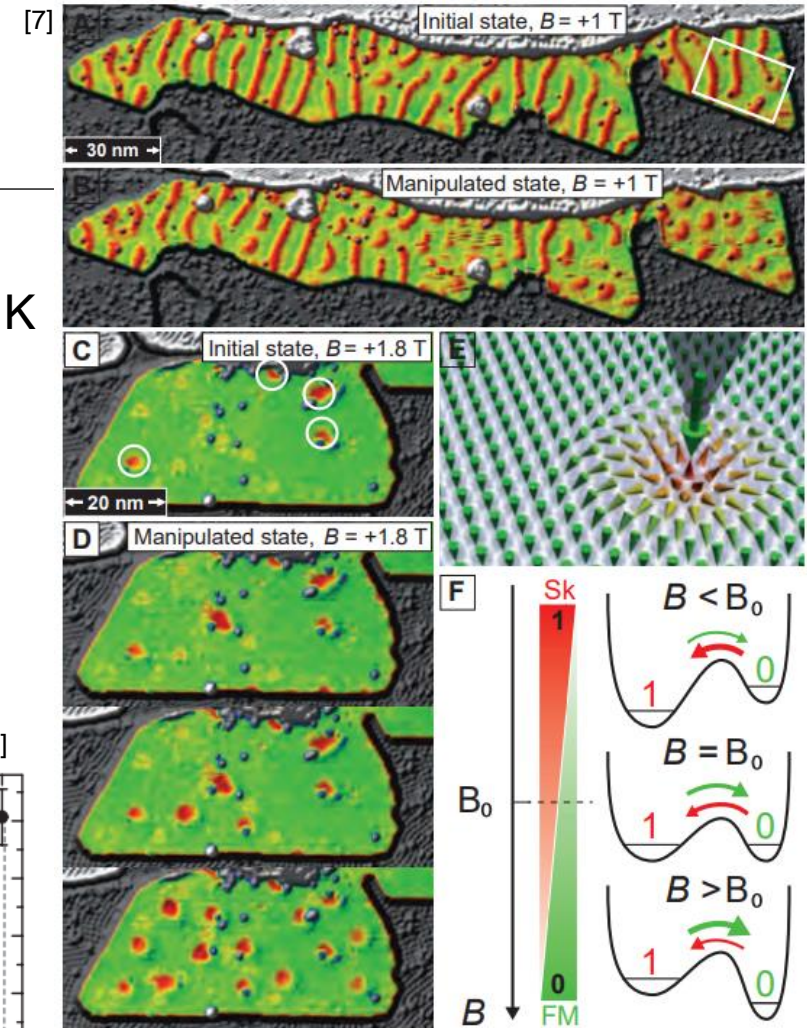
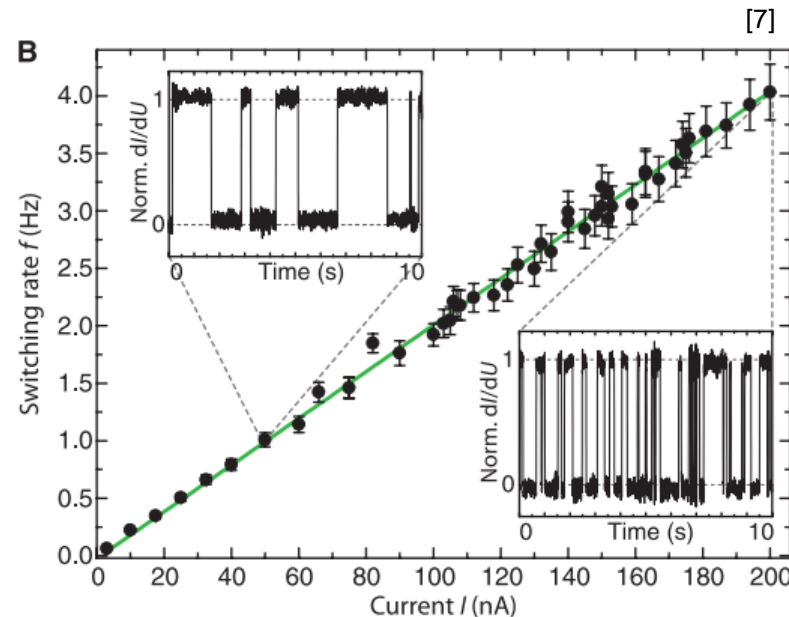


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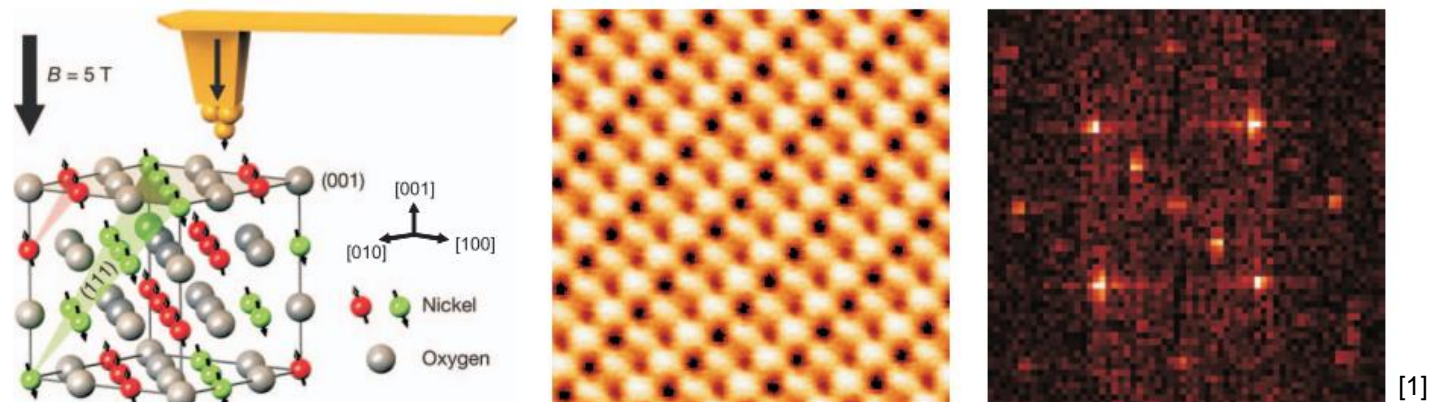


- Switching rate
 - Depends linearly on the tunnel current
 - Also voltage dependent (not shown)

Spin Resolved Microscopy for Insulators?

Outlook: Magnetic Exchange Force Microscopy (MExFM)

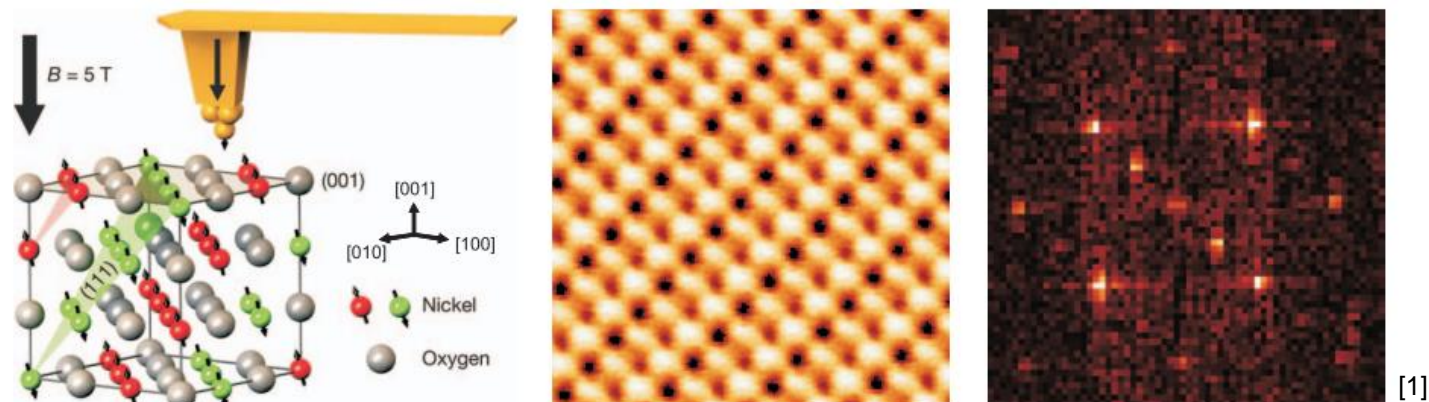
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 - Electromagnetic exchange forces are used to deflect a cantilever that carries the probe tip
- Modes of operation
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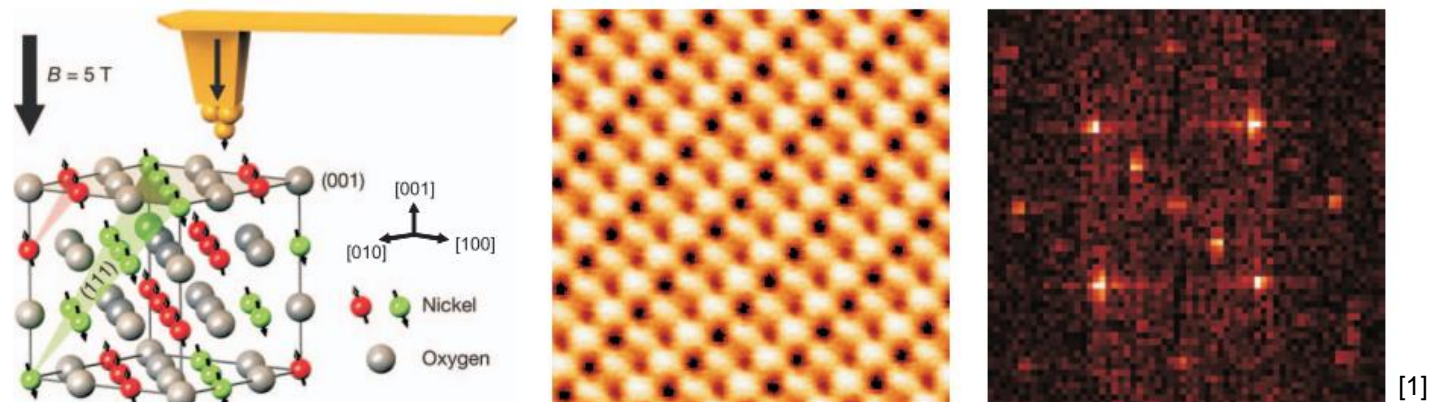
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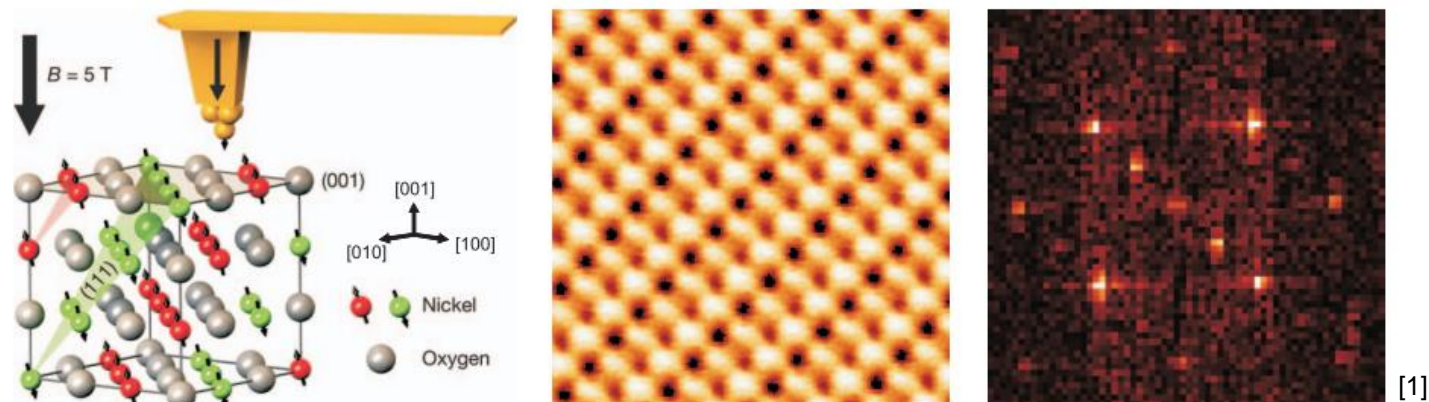
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 - “Non-contact-mode”: dynamic mode of operation, oscillating of the tip near resonant frequency, interaction forces change the resonant frequency
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Head-to-head Comparison: MExFM ↔ SP-STM

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- Temperature range
- UHV environment
- Supports probing with external magnetic fields
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- Precision and complexity
 - Comparable in terms of cost & effort
 - STM is often said to have better resolution however both can achieve atom-scale-resolution
 - SP-STM more applications in research (spin based), while AFM more widespread in the industry

Final Overview

Summary and Conclusion

- Methods allow for probing on atomic scale
- Magnetic moment can be resolved locally
- Possible for metals, as well as insulators
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- Active manipulation of sample possible (on measurement-scale)

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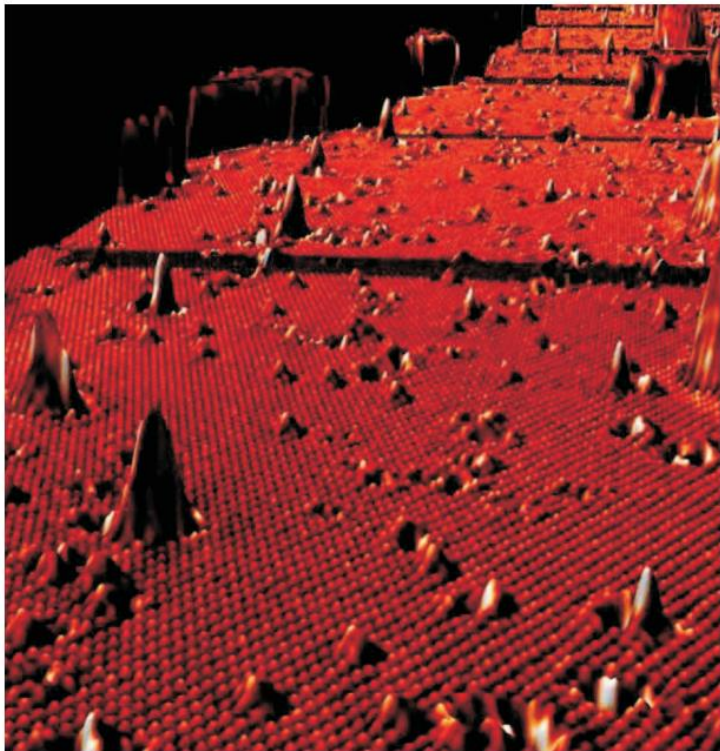
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 - Construct custom test environments for wavefunctions
 - Manipulate/create individual molecules for chemical research

Thank you for your kind attention



[1]

References

Text and Image References

- [1] Spin mapping at the nanoscale and atomic scale (Wiesendanger 2009)
- [2] Introduction to Scanning Tunneling Microscopy (Chen 2007)
- [3] Observation of vacuum tunneling of spin-polarized electrons with the scanning tunneling microscope (Wiesendanger 1990)
- [4] Atomic resolution in scanning force microscopy: Concepts, requirements, contrast mechanisms, and image interpretation (Schwarz 2000)
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- [8] Confinement of Electrons to Quantum Corrals on a Metal Surface (Crommie 1993)
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